

Notice of References Cited	Application/Control No. 10/618,688	Applicant(s)/Patent Under Reexamination NATORI ET AL.	
	Examiner Christian Wilson	Art Unit 2824	Page 1 of 1

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	U	Okamura <i>et al.</i> , Fabrication of Ferroelectric Microcapacitors with Self-Aligned Top Electrodes by Electron-Beam-Induced Patterning Process, <i>Jpn. J. Appl. Phys.</i> , 41 (Nov 2002) 6754.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.